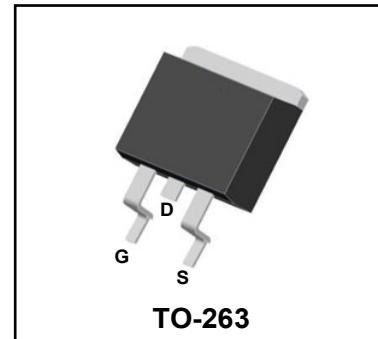


WMM023N08HGS

80V N-Channel Enhancement Mode Power MOSFET

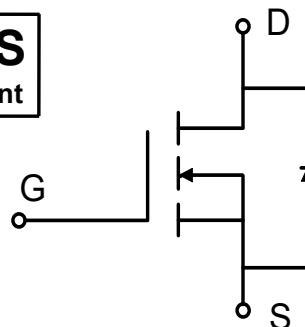
Description

WMM023N08HGS uses Wayon's advanced power trench MOSFET technology that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance. This device is well suited for high efficiency fast switching applications.



Features

- $V_{DS} = 80V$, $I_D = 270A$
- $R_{DS(on)} < 2.6m\Omega$ @ $V_{GS} = 10V$
- High Speed Power Switching
- Low Gate Charge
- Low $R_{DS(ON)}$
- 100% EAS Guaranteed



Applications

- DC/DC Converter
- Power Management Switching
- Motor Driver

Absolute Maximum Ratings ($T_A = 25^\circ C$, unless otherwise noted)

| Parameter | Symbol | Value | Unit |
|--|-------------------|------------|------|
| Drain-Source Voltage | V_{DS} | 80 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Continuous Drain Current <small>$T_c=25^\circ C$</small> | I_D | 270 | A |
| | | 171 | |
| Pulsed Drain Current ¹ | I_{DM} | 1080 | A |
| Single Pulse Avalanche Energy ² | EAS | 625 | mJ |
| Total Power Dissipation | P_D | 329 | W |
| Operating Junction and Storage Temperature Range | T_J , T_{STG} | -55 to 150 | °C |

Thermal Characteristics

| Parameter | Symbol | Value | Unit |
|--|-----------------|-------|------|
| Thermal Resistance from Junction-to-Ambient ³ | $R_{\theta JA}$ | 59 | °C/W |
| Thermal Resistance from Junction-to-Case | $R_{\theta JC}$ | 0.38 | °C/W |

Electrical Characteristics ($T_J = 25^\circ\text{C}$, unless otherwise noted)

| Parameter | Symbol | Test Conditions | Min. | Typ. | Max. | Unit |
|---|-----------------------------|---|------|------|-----------|------------------|
| Static Characteristics | | | | | | |
| Drain-Source Breakdown Voltage | $V_{(\text{BR})\text{DSS}}$ | $V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$ | 80 | - | - | V |
| Gate-body Leakage current | I_{GSS} | $V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$ | - | - | ± 100 | nA |
| Zero Gate Voltage Drain Current $T_J=25^\circ\text{C}$ | I_{DSS} | $V_{\text{DS}} = 80\text{V}, V_{\text{GS}} = 0\text{V}$ | - | - | 1 | μA |
| $T_J=100^\circ\text{C}$ | | | - | - | 100 | |
| Gate-Threshold Voltage | $V_{\text{GS}(\text{th})}$ | $V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$ | 2 | 3 | 4 | V |
| Drain-Source on-Resistance ⁴ | $R_{\text{DS}(\text{on})}$ | $V_{\text{GS}} = 10\text{V}, I_D = 20\text{A}$ | - | 2 | 2.6 | $\text{m}\Omega$ |
| Forward Transconductance ⁴ | g_{fs} | $V_{\text{DS}} = 10\text{V}, I_D = 20\text{A}$ | - | 70 | - | S |
| Dynamic Characteristics⁵ | | | | | | |
| Input Capacitance | C_{iss} | $V_{\text{DS}} = 40\text{V}, V_{\text{GS}} = 0\text{V}, f = 1\text{MHz}$ | - | 8750 | - | pF |
| Output Capacitance | C_{oss} | | - | 1475 | - | |
| Reverse Transfer Capacitance | C_{rss} | | - | 95 | - | |
| Gate Resistance | R_g | $f = 1\text{MHz}$ | - | 2.4 | - | Ω |
| Switching Characteristics⁵ | | | | | | |
| Total Gate Charge | Q_g | $V_{\text{GS}} = 10\text{V}, V_{\text{DS}} = 40\text{V}, I_D = 20\text{A}$ | - | 145 | - | nC |
| Gate-Source Charge | Q_{gs} | | - | 38.5 | - | |
| Gate-Drain Charge | Q_{gd} | | - | 39 | - | |
| Turn-on Delay Time | $t_{\text{d(on)}}$ | $V_{\text{GS}} = 10\text{V}, V_{\text{DD}} = 40\text{V}, R_G = 3\Omega, I_D = 20\text{A}$ | - | 27.5 | - | ns |
| Rise Time | t_r | | - | 53 | - | |
| Turn-off Delay Time | $t_{\text{d(off)}}$ | | - | 87 | - | |
| Fall Time | t_f | | - | 53 | - | |
| Body Diode Reverse Recovery Time | t_{rr} | $I_F = 20\text{A}, dI/dt = 100\text{A}/\mu\text{s}$ | - | 88 | - | ns |
| Body Diode Reverse Recovery Charge | Q_{rr} | | - | 110 | - | nC |
| Drain-Source Body Diode Characteristics | | | | | | |
| Diode Forward Voltage ⁴ | V_{SD} | $I_S = 20\text{A}, V_{\text{GS}} = 0\text{V}$ | - | - | 1.2 | V |
| Continuous Source Current | $T_C = 25^\circ\text{C}$ | I_S | - | - | 270 | A |

Notes:

1. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})} = 150^\circ\text{C}$.
2. The EAS data shows Max. rating . The test condition is $V_{\text{DD}} = 25\text{V}, V_{\text{GS}} = 10\text{V}, L = 0.5\text{mH}, I_{\text{AS}} = 50\text{A}$.
3. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed , pulse width $\leq 300\text{us}$, duty cycle $\leq 2\%$.
5. This value is guaranteed by design hence it is not included in the production test.

Typical Characteristics

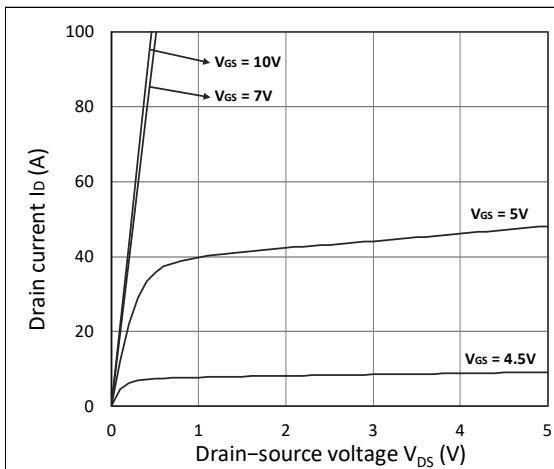


Figure 1. Output Characteristics

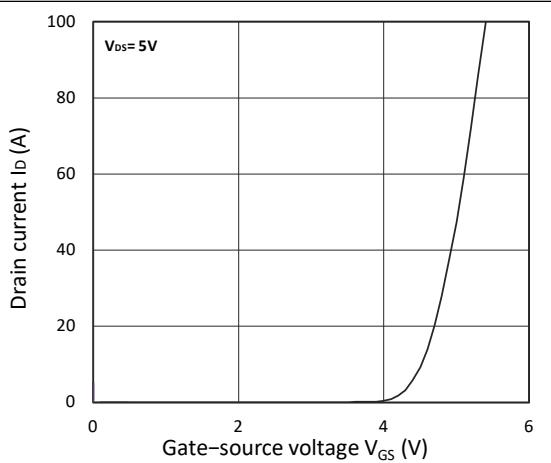


Figure 2. Transfer Characteristics

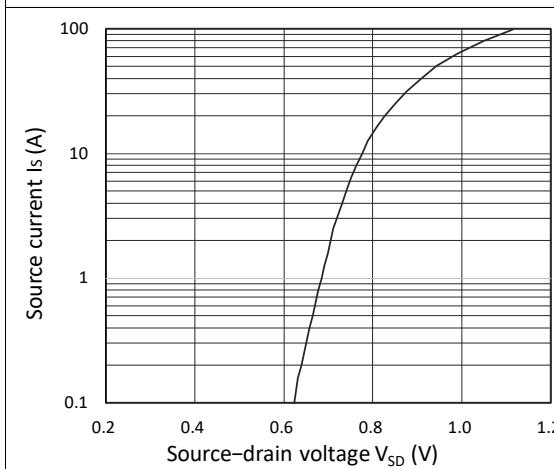
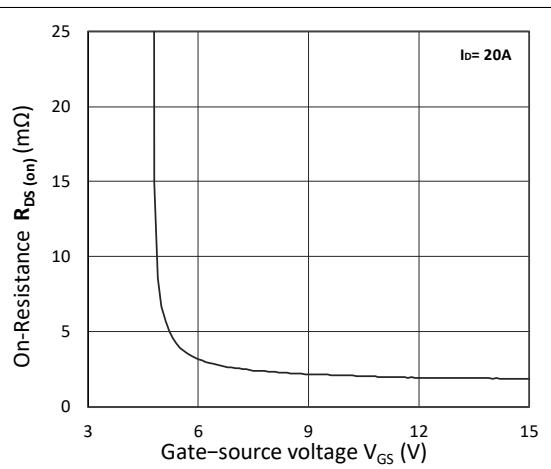
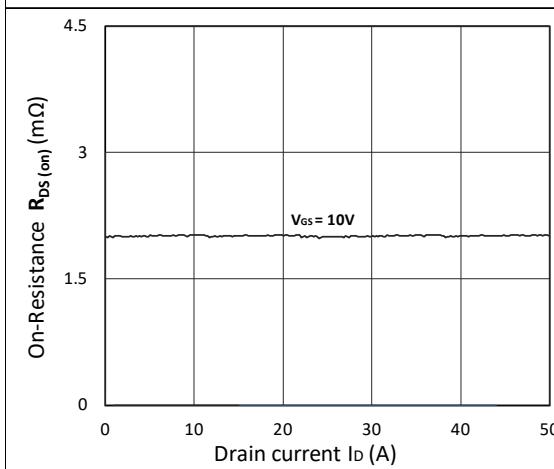
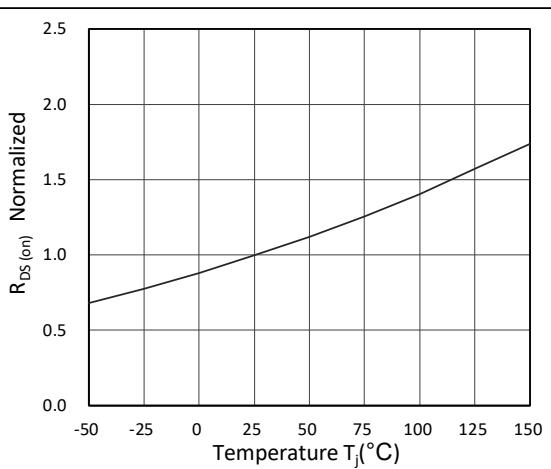
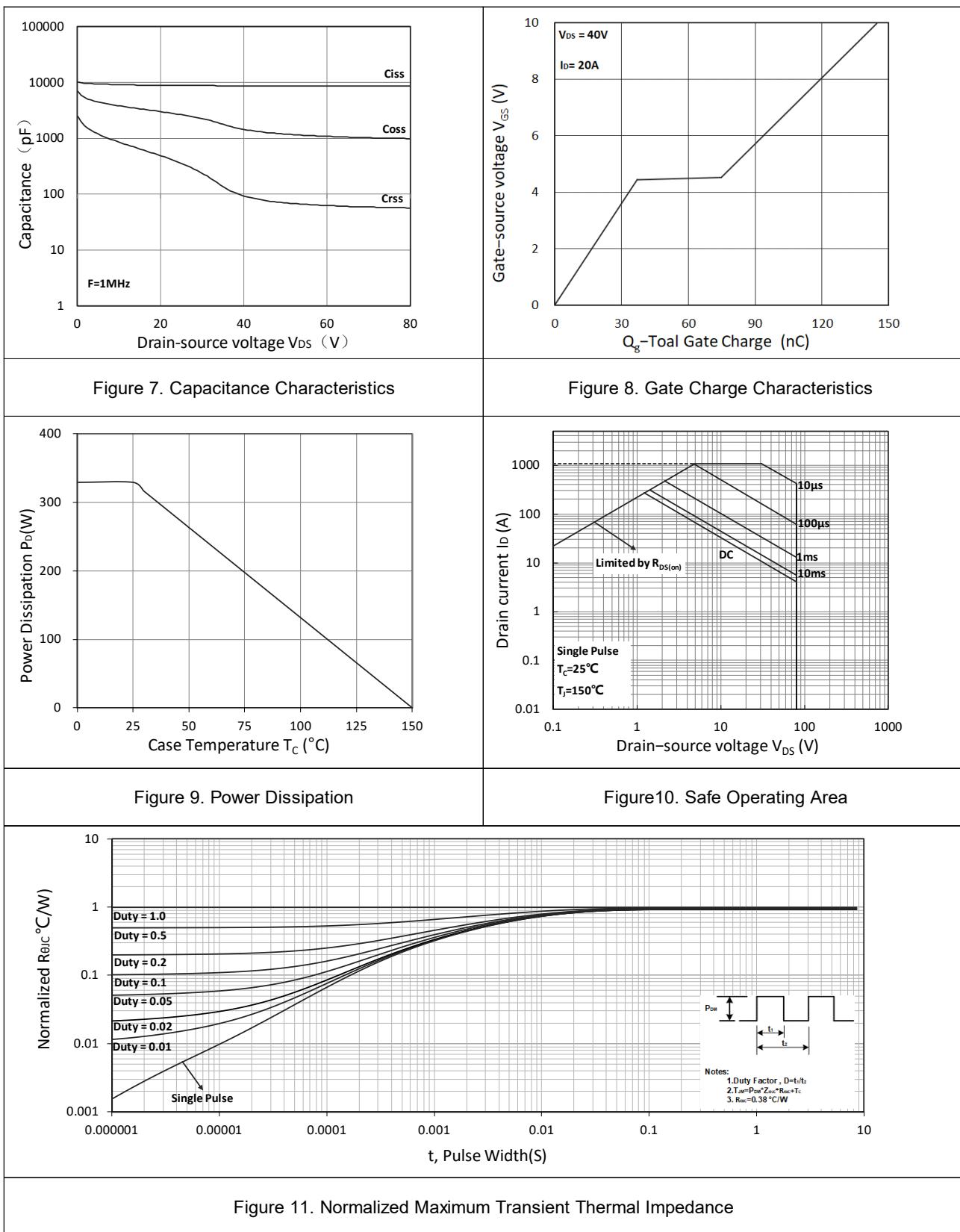
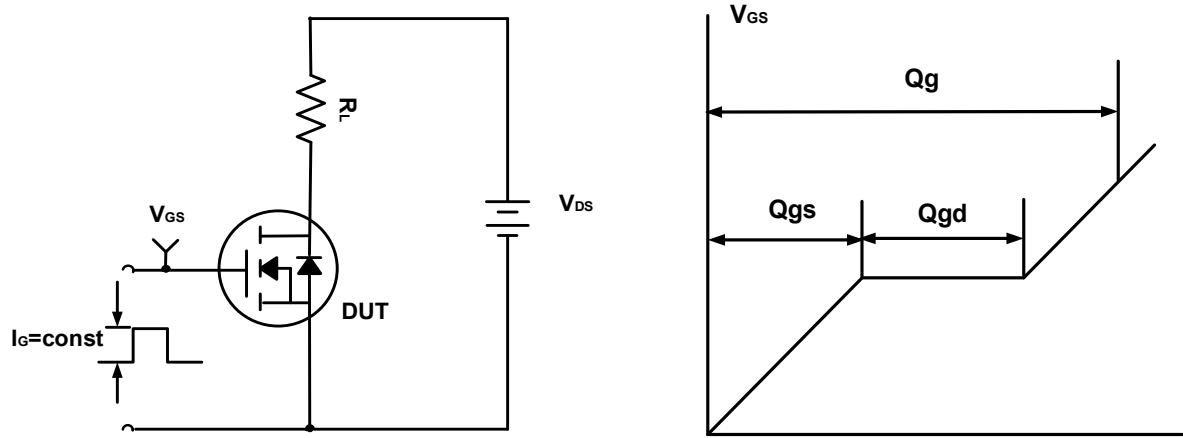
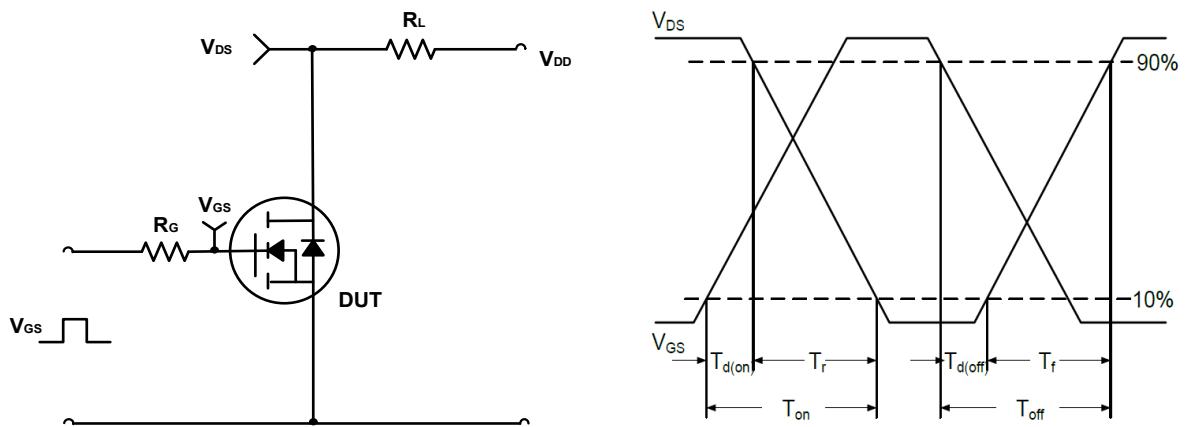
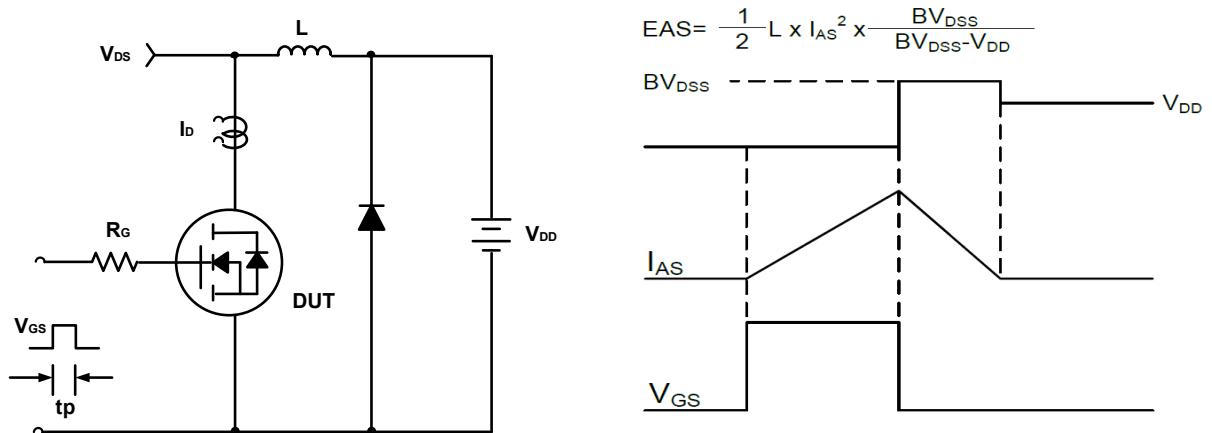


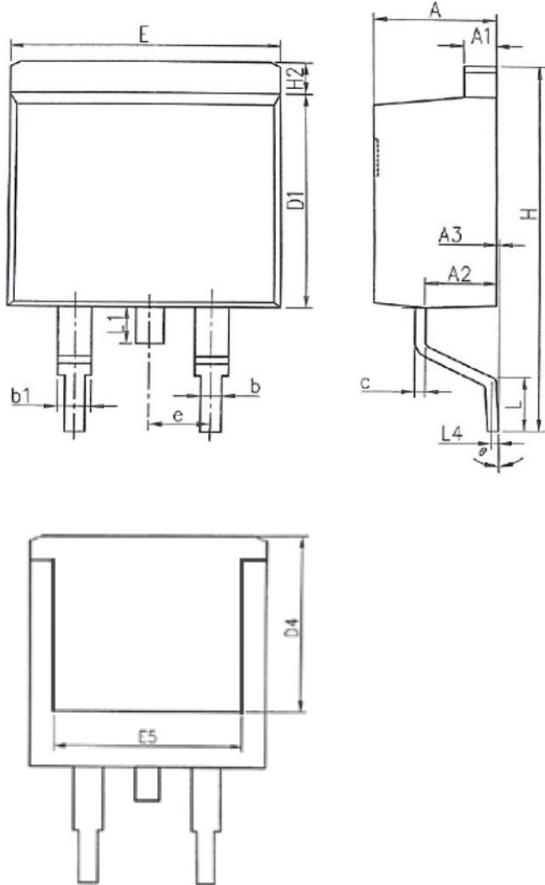
Figure 3. Forward Characteristics of Reverse

Figure 4. $R_{DS(\text{on})}$ vs. V_{GS} Figure 5. $R_{DS(\text{on})}$ vs. I_D Figure 6. Normalized $R_{DS(\text{on})}$ vs. Temperature



Test Circuit**Figure A. Gate Charge Test Circuit & Waveforms****Figure B. Switching Test Circuit & Waveforms****Figure C. Unclamped Inductive Switching Circuit & Waveforms**

Mechanical Dimensions for TO-263

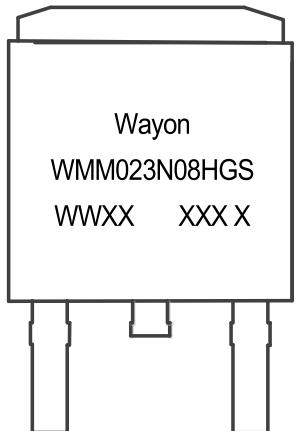


COMMON DIMENSIONS

| SYMBOL | MM | |
|--------|----------|-------|
| | MIN | MAX |
| A | 4.37 | 4.89 |
| A1 | 1.17 | 1.42 |
| A2 | 2.20 | 2.90 |
| A3 | 0.00 | 0.25 |
| b | 0.70 | 0.96 |
| b1 | 1.17 | 1.47 |
| c | 0.28 | 0.60 |
| D1 | 8.45 | 9.30 |
| D4 | 6.60 | - |
| E | 9.80 | 10.40 |
| E5 | 7.06 | - |
| e | 2.54BSC | |
| H | 14.70 | 15.70 |
| H2 | 1.07 | 1.47 |
| L | 2.00 | 2.80 |
| L1 | - | 1.75 |
| L4 | 0.254BSC | |
| θ | 0° | 9° |

Ordering Information

| Part | Package | Marking | Packing method |
|--------------|---------|--------------|----------------|
| WMM023N08HGS | TO-263 | WMM023N08HGS | Tape and Reel |

Marking Information

WMM023N08HGS = Device code

WWXX XXX X= Date code